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5	BRS	L4	5	williams-ant\$.in. and @pd>20020922	USPA T; US-P GPUB	2003/05/15 16:58	Rev'd images
6	BRS	L6	0	(OLE) and @ad<19920617 and (OOP or (object adj1 oriented)) and @pd>20020922	USPA T; US-P GPUB	2003/05/15 16:58	
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10	BRS	L10	0	((709/328).CCLS.) and @ad<19920617 and @pd>20020922	USPA T; US-P GPUB	2003/05/15 17:00	

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11	BRS	L11	0	5261080.uref. and @ad<19920617 and @pd>20020922	USPA T; US-P GPUB	2003/05/1 5 16:59	
12	BRS	L12	0	((server or servers) same (register\$3 or registra\$6 or locat\$5)) and @ad<19920617 and @pd>20020922	USPA T; US-P GPUB	2003/05/1 5 17:00	
13	BRS	L13	0	(registry or registries) and @ad<19920617 and 709/\$.ccls. and @pd>20020922	USPA T; US-P GPUB	2003/05/1 5 17:00	
14	IS&R	L14	3921	((709/315-316) or (709/203)).CCLS.	USPA T; US-P GPUB	2003/05/1 5 17:00	
15	BRS	L15	0	L14 and @ad<19920617 and @pd>20020922	USPA T; US-P GPUB	2003/05/1 5 17:01	
16	BRS	L17	156	ole and (compound adj1 document\$1)	USPA T; US-P GPUB	2003/05/1 5 17:11	
17	BRS	L18	37	L16 not (L17 or L4)	USPA T; US-P GPUB	2003/05/1 5 17:11	
18	BRS	L16	37	(compound adj1 document\$1) and @ad<19920617	USPA T; US-P GPUB	2003/05/1 5 17:20	Rev'd kwic + images
19	BRS	L19	22	(compound adj1 document\$1) and @pd<19920617	EPO; JPO; DERW ENT; IBM_ TDB	2003/05/1 5 17:20	Rev'd kwic + images

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*Onuki, J.; Koubuchi, Y.; Suwa, M.; Koizumi, M.; Gardner, D.S.;
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